



circuit + coverage report

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M Abramovici - Test Conference, 1993. Proceedings., International, 1993 -
[ieeexplore.ieee.org](#)

... is usually specified as detectable fault **coverage**, DFC=D ... Some ATPG programs
report

their results in terms of ... are detected since the entire **circuit** is untestable ...

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[Coverage Analysis Techniques for HDL Design Validation - group of 2 »](#)
JY Jou, CNJ Liu - the 6th Asia Pacific Conference on cHip Design Languages, ..., 1999 -
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... The basic idea of this **coverage** metric is to view a **circuit** as computing a ... If only
partial coverage report is required, we can retrieve only partial data from ...

[Cited by 8](#) - [Related Articles](#) - [View as HTML](#) - [Web Search](#)
[Combinational profiles of sequential benchmark circuits](#)
F Brglez, D Bryan, K Kozminski - Circuits and Systems, 1989., IEEE International
Symposium on, 1989 - [ieeexplore.ieee.org](#)

... part of the paper presents the benchmarks, their essential **circuit** parameters, and
any ... scan-, and sequential-based methods in terms of fault **coverage** and test ...

[Cited by 780](#) - [Related Articles](#) - [Web Search](#)
[RT-level ITC'99 benchmarks and first ATPG results - group of 9 »](#)
F Corno, MS Reorda, G Squillero - Design & Test of Computers, IEEE, 2000 -
[ieeexplore.ieee.org](#)

... The last column **reports** the inherent testability of ... benchmarks, expressed as the
fault **coverage** attained by ... of 10,000 pseudorandom patterns at the **circuit** PIs ...

[Cited by 77](#) - [Related Articles](#) - [Web Search](#) - [BL Direct](#)
[Coverage metrics for functional validation of hardware designs - group of 12](#)

»

S Tasiran, K Keutzer - Design & Test of Computers, IEEE, 2001 - [ieeexplore.ieee.org](#)

... As with code **coverage**, **circuit-structure-based** metrics provide a lower bound on
the amount of required simulation. ... 9 **Coverage** tools then **report** the number ...

[Cited by 42](#) - [Related Articles](#) - [Web Search](#) - [BL Direct](#)
[Random-Pattern Coverage Enhancement and Diagnosis for LSSD Logic Self-Test - group of 2 »](#)
EB Eichelberger, E Lindbloom - IBM Journal of Research and Development, 1983 -
[research.ibm.com](#)

... that exhaustive pattern sets can be applied to ensure complete **coverage** [1-31] ... only
allow partitioning to the required limits with unacceptable **circuit** delays or ...

[Cited by 77](#) - [Related Articles](#) - [View as HTML](#) - [Web Search](#)
[Improving Gate Level Fault Coverage by RTL Fault Grading - group of 4 »](#)
W Mao, RK Gulati - Proc. Int. Test Conf.(ITC), 1996 - [doi.ieeecomputersociety.org](#)

... Section 5 **reports** some of our findings in the ... difference between RTL and gate level
fault coverage. ... Test Pattern Generation (ATPG), testable **circuit** design, etc ...

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